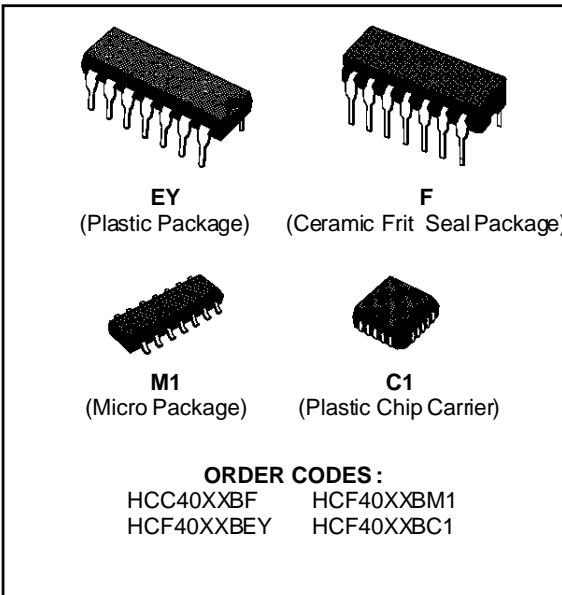


## NAND GATES

**QUAD 2 INPUT HCC/HCF 4011B  
 DUAL 4 INPUT HCC/HCF 4012B  
 TRIPLE 3 INPUT HCC/HCF 4023B**

- PROPAGATION DELAY TIME = 60ns (typ.) AT  $C_L = 50\text{pF}$ ,  $V_{DD} = 10\text{V}$
- BUFFERED INPUTS AND OUTPUTS
- QUIESCENT CURRENT SPECIFIED TO 20V FOR HCC DEVICE
- INPUT CURRENT OF 100nA AT 18V AND 25°C FOR HCC DEVICE
- 100% TESTED FOR QUIESCENT CURRENT
- 5V, 10V AND 15V PARAMETRIC RATINGS
- MEETS ALL REQUIREMENTS OF JEDEC TENTATIVE STANDARD N°. 13A, "STANDARD SPECIFICATIONS FOR DESCRIPTION OF "B" SERIES CMOS DEVICES"

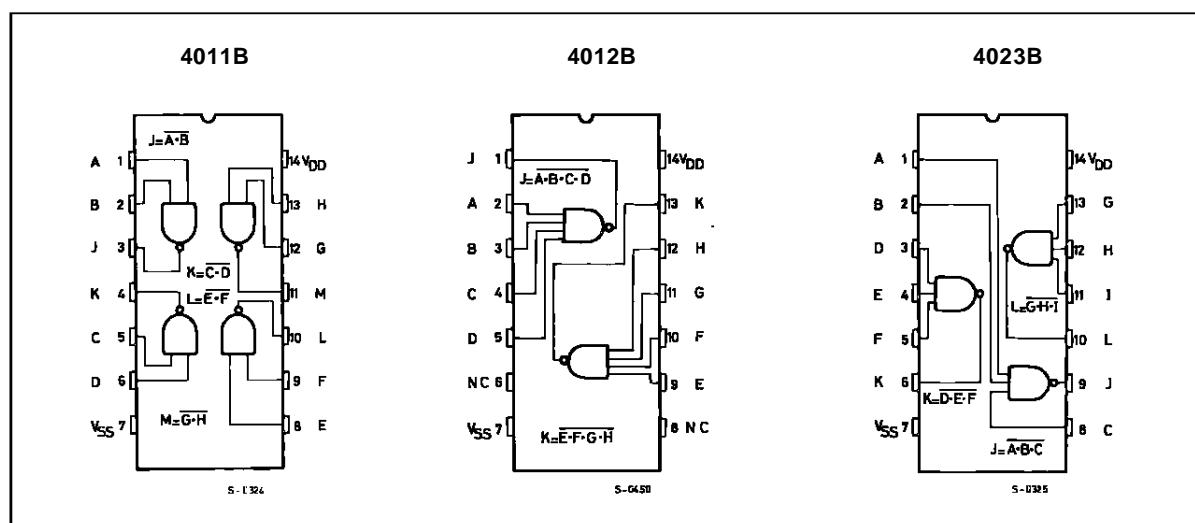


### DESCRIPTION

The **HCC4011B**, **HCC4012B** and **HCC4023B** (extended temperature range) and **HCF4011B**, **HCF4012B** and **HCF4023B** (intermediate temperature range) are monolithic, integrated circuit, available in 14-lead dual in-line plastic or ceramic package and plastic micropackage.

The **HCC/HCF4011B**, **HCC/HCF4012B** and **HCC/HCF4023B** NAND gates provide the system designer with direct implementation of the NAND function and supplement the existing family of COS/MOS gates. All inputs and outputs are buffered.

### PIN CONNECTIONS



## HCC/HFC4011B/12B/23B

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### ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
$V_{DD}^*$	Supply Voltage : <b>HCC</b> Types <b>HCF</b> Types	– 0.5 to + 20 – 0.5 to + 18	V V
$V_i$	Input Voltage	– 0.5 to $V_{DD}$ + 0.5	V
$I_I$	DC Input Current (any one input)	± 10	mA
$P_{tot}$	Total Power Dissipation (per package) Dissipation per Output Transistor for $T_{op}$ = Full Package-temperature Range	200 100	mW mW
$T_{op}$	Operating Temperature : <b>HCC</b> Types <b>HCF</b> Types	– 55 to + 125 – 40 to + 85	°C °C
$T_{stg}$	Storage Temperature	– 65 to + 150	°C

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for external periods may affect device reliability.

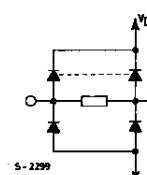
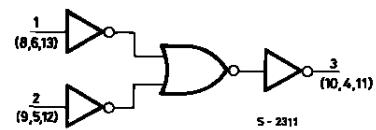
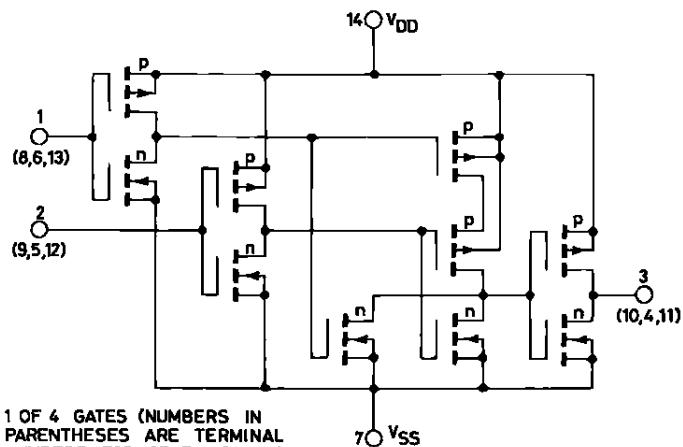
\* All voltage values are referred to  $V_{SS}$  pin voltage.

### RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
$V_{DD}$	Supply Voltage : <b>HCC</b> Types <b>HCF</b> Types	3 to 18 3 to 15	V V
$V_i$	Input Voltage	0 to $V_{DD}$	V
$T_{op}$	Operating Temperature : <b>HCC</b> Types <b>HCF</b> Types	– 55 to + 125 – 40 to + 85	°C °C

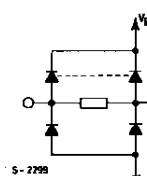
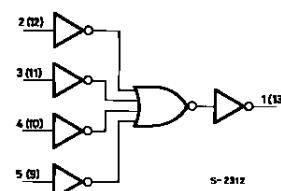
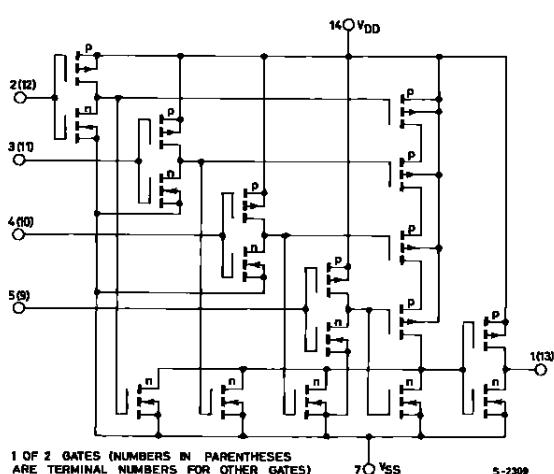
**SCHEMATIC AND LOGIC DIAGRAMS**

**4011B**



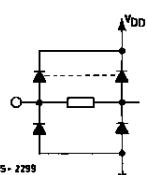
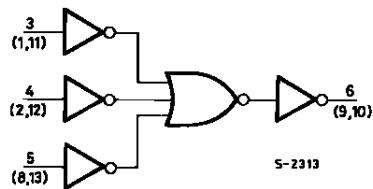
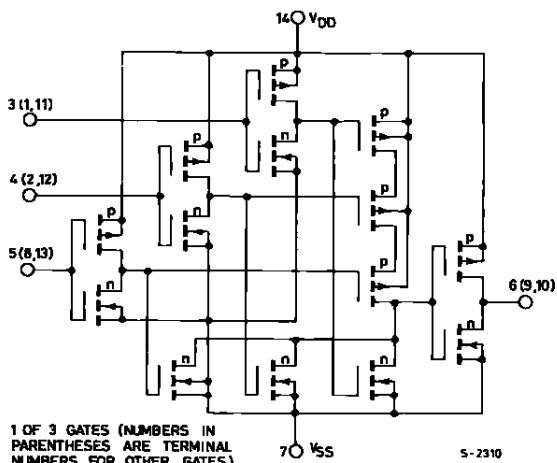
ALL INPUTS ARE PROTECTED BY COS/MOS PROTECTION NETWORK

**4012B**



ALL INPUTS ARE PROTECTED BY COS/MOS PROTECTION NETWORK

**4023B**



ALL INPUTS ARE PROTECTED BY COS/MOS PROTECTION NETWORK

## HCC/HFC4011B/12B/23B

### STATIC ELECTRICAL CHARACTERISTICS (over recommended operating conditions)

Symbol	Parameter	Test Conditions				Value						Unit		
		V <sub>I</sub> (V)	V <sub>O</sub> (V)	I <sub>OL</sub>   (μA)	V <sub>DD</sub> (V)	T <sub>Low</sub> *		25°C			T <sub>High</sub> *			
						Min.	Max.	Min.	Typ.	Max.	Min.	Max.		
I <sub>L</sub>	Quiescent Current	HCC Types	0/5		5		0.25		0.01	0.25		7.5	μA	
			0/10		10		0.5		0.01	0.5		15		
			0/15		15		1		0.01	1		30		
			0/20		20		5		0.02	5		150		
	HCF Types	HCF Types	0/5		5		1		0.01	1		7.5		
			0/10		10		2		0.01	2		15		
			0/15		15		4		0.01	4		30		
V <sub>OH</sub>	Output High Voltage		0/5	< 1	5	4.95		4.95			4.95		V	
			0/10	< 1	10	9.95		9.95			9.95			
			0/15	< 1	15	14.95		14.95			14.95			
V <sub>OL</sub>	Output Low Voltage		5/0	< 1	5		0.05			0.05		0.05	V	
			10/0	< 1	10		0.05			0.05		0.05		
			15/0	< 1	15		0.05			0.05		0.05		
V <sub>IH</sub>	Input High Voltage		0.5/4.5	< 1	5	3.5		3.5			3.5		V	
			1/9	< 1	10	7		7			7			
			1.5/13.5	< 1	15	11		11			11			
V <sub>IL</sub>	Input Low Voltage		4.5/0.5	< 1	5		1.5			1.5		1.5	V	
			9/1	< 1	10		3			3		3		
			13.5/1.5	< 1	15		4			4		4		
I <sub>OH</sub>	Output Drive Current	HCC Types	0/5	2.5		5	-2		-1.6	-3.2		-1.15	mA	
			0/5	4.6		5	-0.64		-0.51	-1		-0.36		
			0/10	9.5		10	-1.6		-1.3	-2.6		-0.9		
			0/15	13.5		15	-4.2		-3.4	-6.8		-2.4		
		HCF Types	0/5	2.5		5	-1.53		-1.36	-3.2		-1.1		
			0/5	4.6		5	-0.52		-0.44	-1		-0.36		
			0/10	9.5		10	-1.3		-1.1	-2.6		-0.9		
			0/15	13.5		15	-3.6		-3.0	-6.8		-2.4		
I <sub>OL</sub>	Output Sink Current	HCC Types	0/5	0.4		5	0.64		0.51	1		0.36	mA	
			0/10	0.5		10	1.6		1.3	2.6		0.9		
			0/15	1.5		15	4.2		3.4	6.8		2.4		
		HCF Types	0/5	0.4		5	0.52		0.44	1		0.36		
			0/10	0.5		10	1.3		1.1	2.6		0.9		
			0/15	1.5		15	3.6		3.0	6.8		2.4		
			0/18	Any Input		18		± 0.1		±10 <sup>-5</sup>	± 0.1		± 1	
			0/15			15		± 0.3		±10 <sup>-5</sup>	± 0.3		± 1	
C <sub>I</sub>	Input Capacitance		Any Input							5	7.5		pF	

\* T<sub>LOW</sub> = -55°C for HCC device : -40°C for HCF device.

\* T<sub>HIGH</sub> = +125°C for HCC device : +85°C for HCF device.

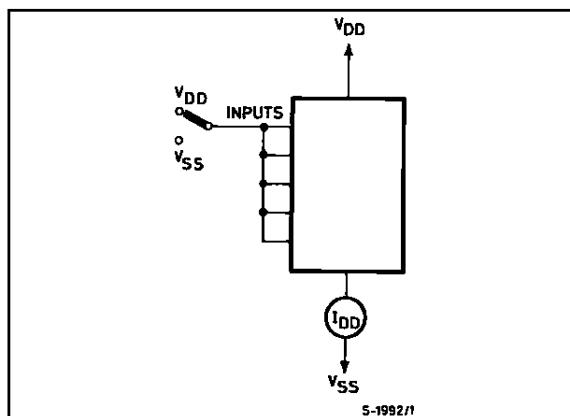
The Noise Margin for both "1" and "0" level is : 1V min. with V<sub>DD</sub> = 5V, 2V min. with V<sub>DD</sub> = 10V, 2.5V with V<sub>DD</sub> = 15V.

**DYNAMIC ELECTRICAL CHARACTERISTICS** ( $T_{amb} = 25^\circ C$ ,  $C_L = 50\text{pF}$ ,  $R_L = 200\text{k}\Omega$ , typical temperature coefficient for all  $V_{DD}$  values is  $0.3\%/^\circ C$ , all input rise and fall times = 20ns)

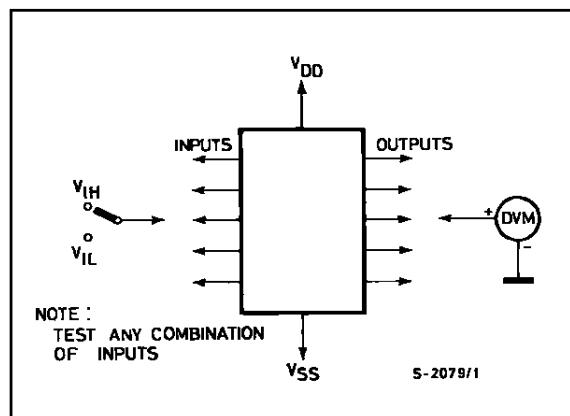
Symbol	Parameter	Test Conditions			Value	Unit
			$V_{DD}$ (V)	Min.	Typ.	
$t_{PLH}, t_{PHL}$	Propagation Delay Time		5		125	250
			10		60	120
			15		45	90
$t_{THL}, t_{TLH}$	Transition Time		5		100	200
			10		50	100
			15		40	80

### TEST CIRCUITS

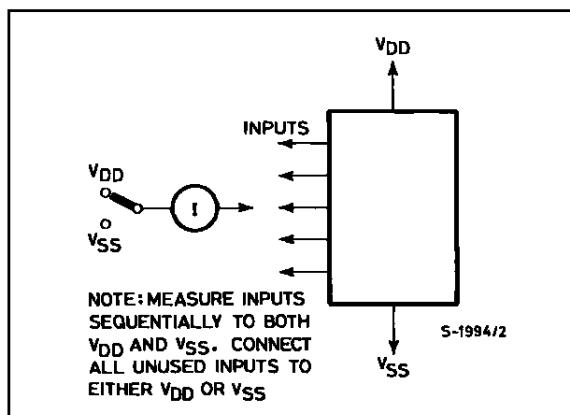
Quiescent Device Current.



Noise Immunity.

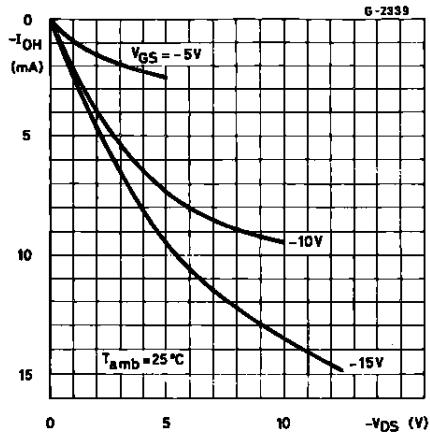


Input Leakage Current.

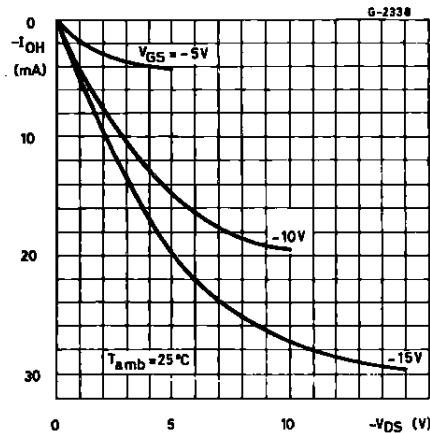


## HCC/HFC4011B/12B/23B

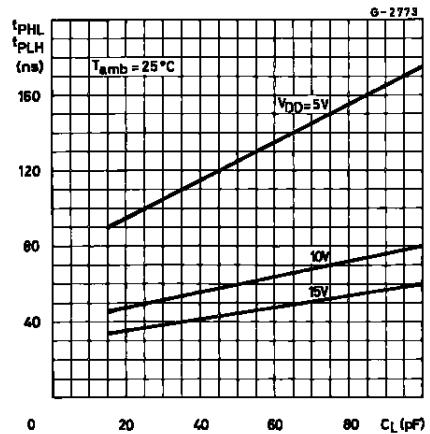
Minimum Output High (source) Current Characteristics.



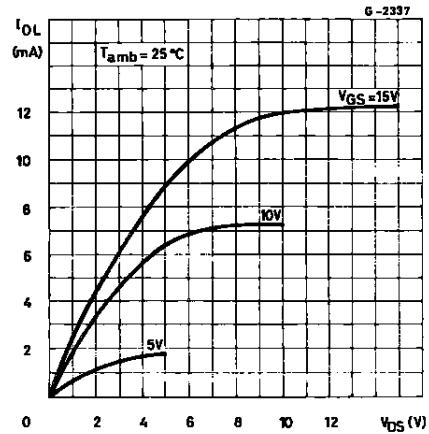
Typical Output High (source) Current Characteristics.



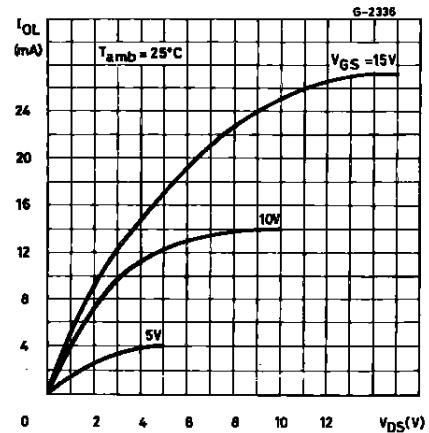
Typical Propagation Delay Time per Gate as a Function of Load Capacitance.



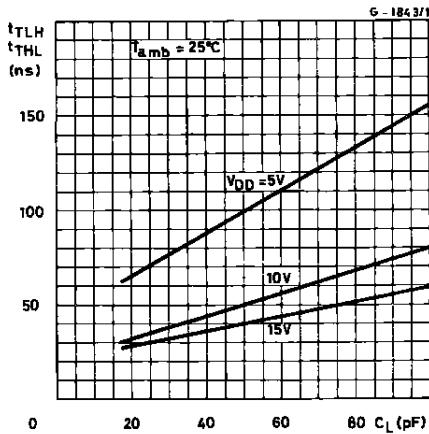
Minimum Output Low (sink) Current Characteristics.



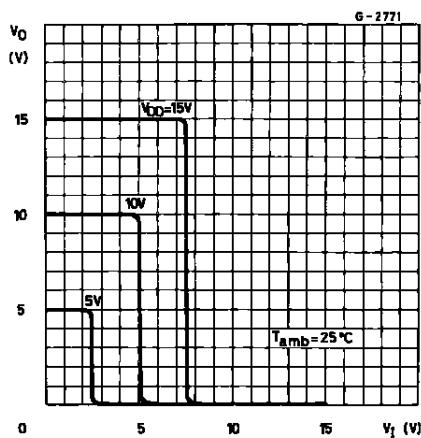
Typical Output Low (sink) Current Characteristics.



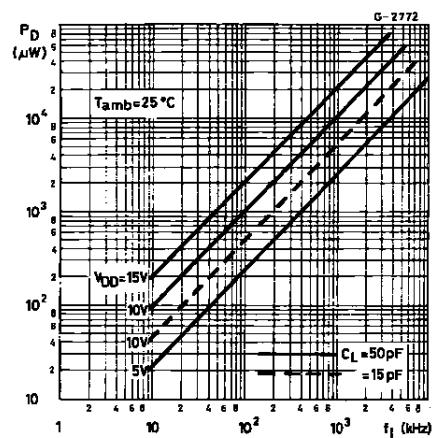
Typical Transition Time vs. Load Capacitance.



Typical Voltage Transfer Characteristics.

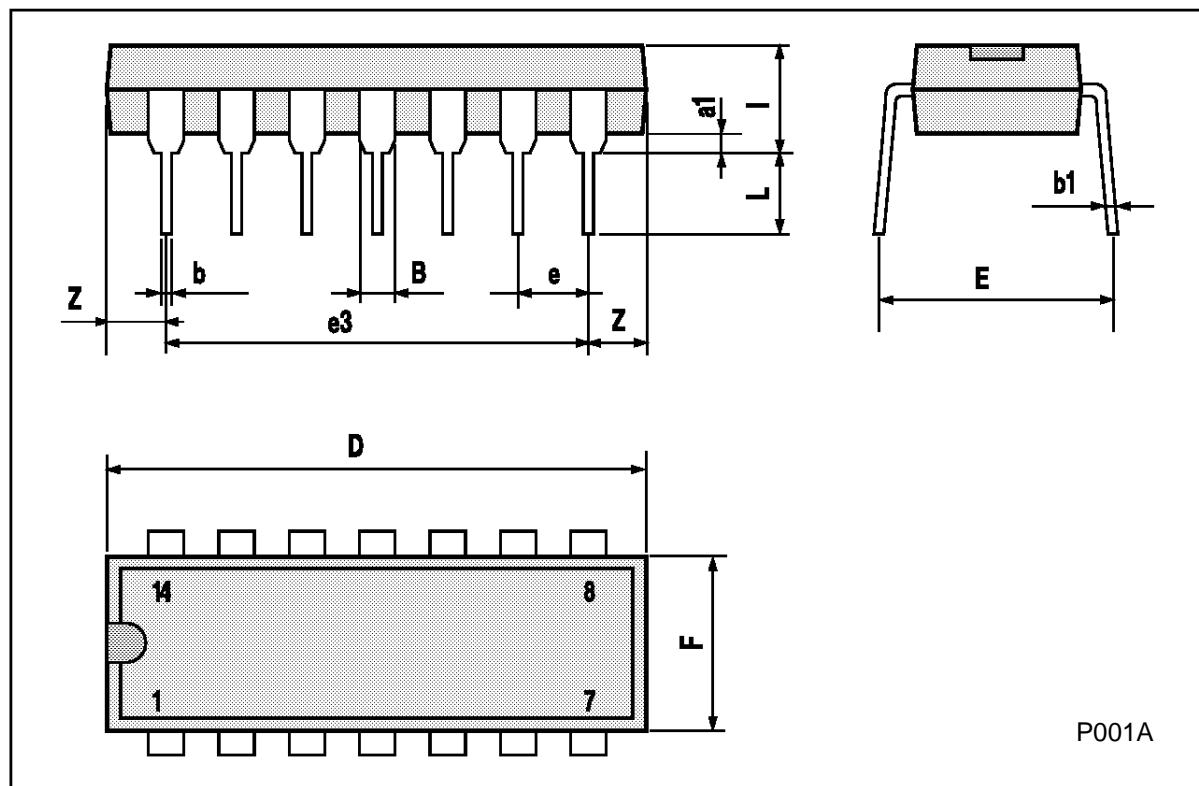


Typical Power Dissipation/gate vs Frequency.



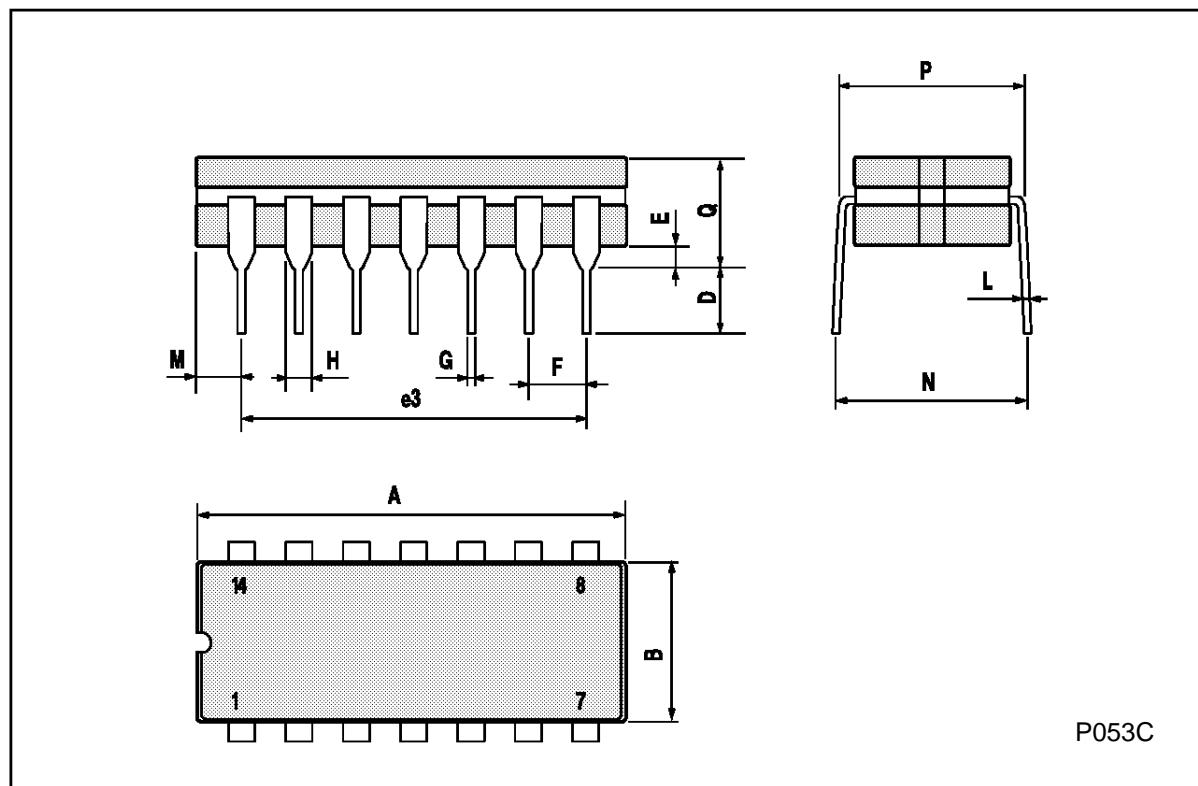
**Plastic DIP14 MECHANICAL DATA**

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
a1	0.51			0.020		
B	1.39		1.65	0.055		0.065
b		0.5			0.020	
b1		0.25			0.010	
D			20			0.787
E		8.5			0.335	
e		2.54			0.100	
e3		15.24			0.600	
F			7.1			0.280
I			5.1			0.201
L		3.3			0.130	
Z	1.27		2.54	0.050		0.100



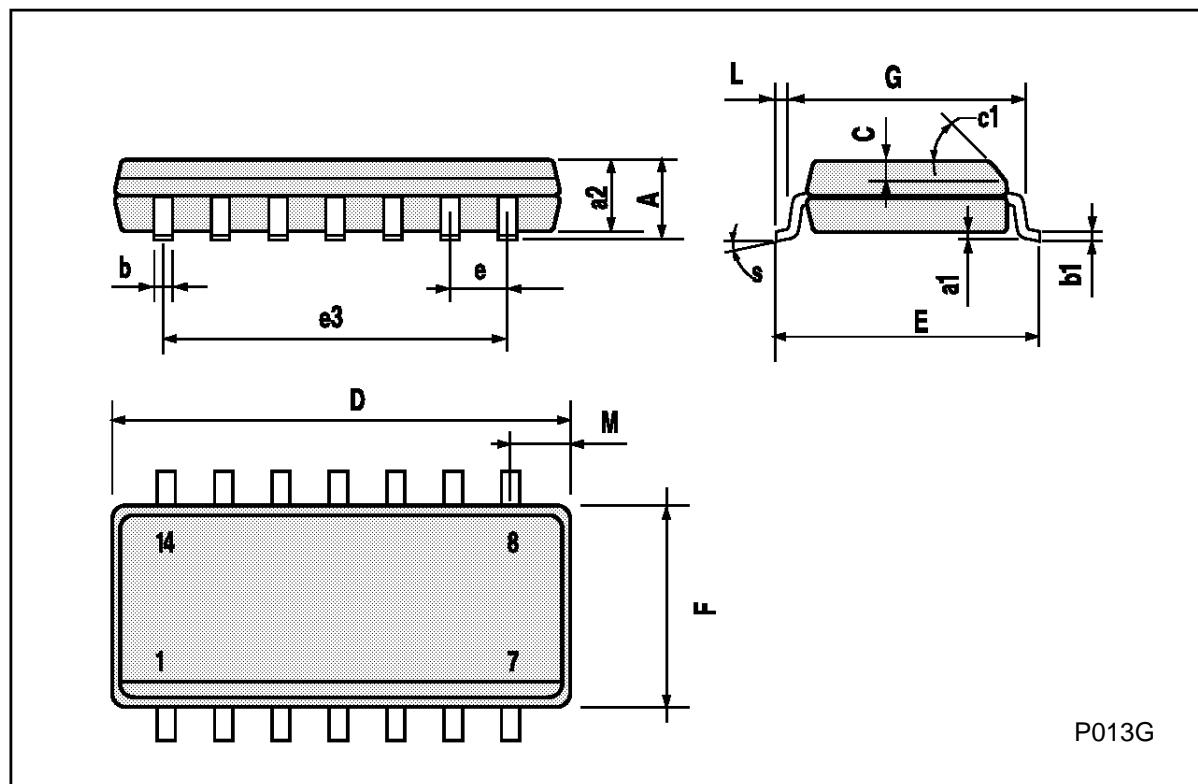
Ceramic DIP14/1 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			20			0.787
B			7.0			0.276
D		3.3			0.130	
E	0.38			0.015		
e3		15.24			0.600	
F	2.29		2.79	0.090		0.110
G	0.4		0.55	0.016		0.022
H	1.17		1.52	0.046		0.060
L	0.22		0.31	0.009		0.012
M	1.52		2.54	0.060		0.100
N			10.3			0.406
P	7.8		8.05	0.307		0.317
Q			5.08			0.200



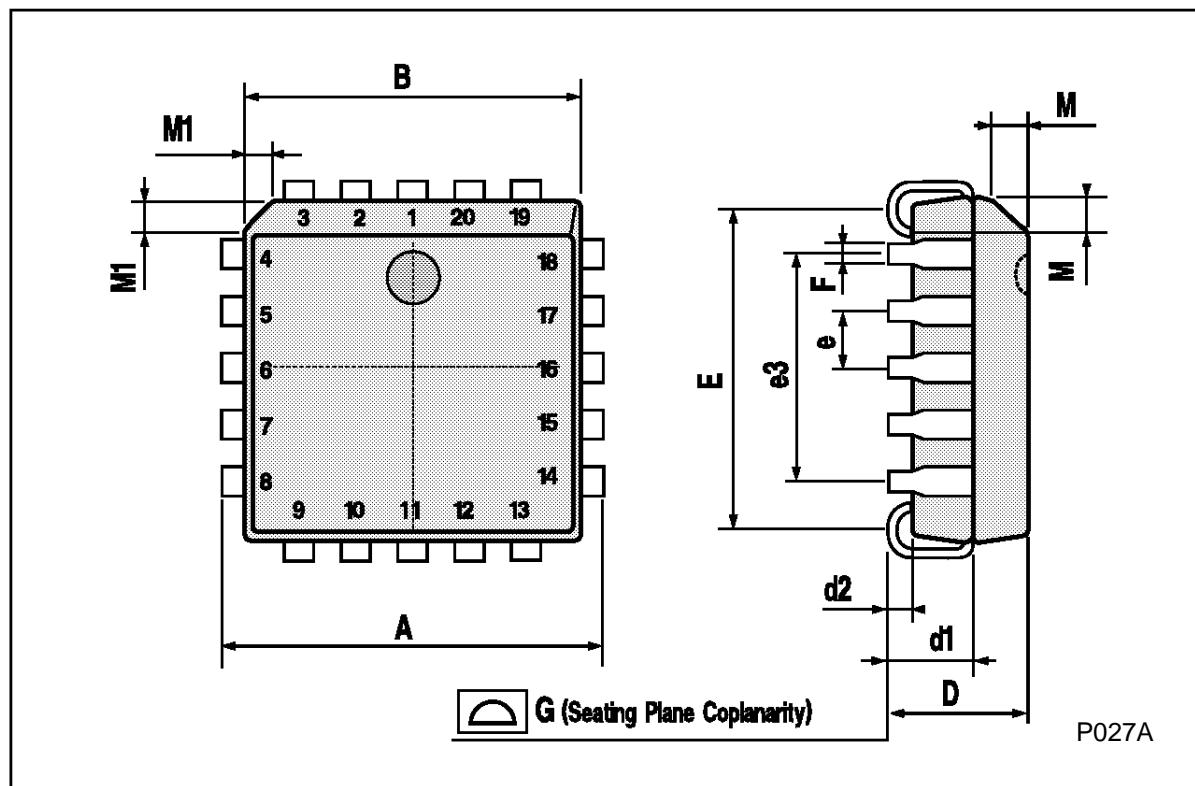
**SO14 MECHANICAL DATA**

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.003		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1	45° (typ.)					
D	8.55		8.75	0.336		0.344
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		7.62			0.300	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.68			0.026
S	8° (max.)					



**PLCC20 MECHANICAL DATA**

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	9.78		10.03	0.385		0.395
B	8.89		9.04	0.350		0.356
D	4.2		4.57	0.165		0.180
d1		2.54			0.100	
d2		0.56			0.022	
E	7.37		8.38	0.290		0.330
e		1.27			0.050	
e3		5.08			0.200	
F		0.38			0.015	
G			0.101			0.004
M		1.27			0.050	
M1		1.14			0.045	



P027A

## **HCC/HFC4011B/12B/23B**

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